

Form PTO-419 SEP 17 2004 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1196		SERIAL NO. 09/388,063			
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Vishnu K. Agarwal et al.			
				FILING DATE Aug. 30, 1999			
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
[Signature]	AA	4,261,698	04/81	Carr et al.			
	AB	4,691,662	09/87	Roppel et al.			
	AC	5,261,961	11/93	Takasu et al.			
	AD	5,270,241	12/93	Dennison et al.			
	AE	5,312,783	05/94	Takasaki et al.			
	AF	5,392,189	02/95	Fazan et al.			
	AG	5,395,771	03/95	Nakato			
	AH	5,468,687	11/95	Carl et al.			
	AI	5,525,156	06/96	Manada et al.			
	AJ	5,614,018	03/97	Azuma et al.			
[Signature]	AK	5,656,329	08/97	Hampden-Smith			
	AL	5,663,089	09/97	Tomozawa et al.			
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
[Signature]							Yes No
	AM	EP 0 030 798	06/81	EPO - Hughes			N/A
	AN	GB 2 194 555 A	03/88	UK - Nippon			N/A
	AO	EP 0 306 069 A2	03/89	EPO - Phillips			N/A
	AP	EP 0 388 957 A2	09/90	EP - NEC Corp			N/A
AQ	JP 2250970	10/90	Japan - NEC Corp			ABS	
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)							
[Signature]	AR	Aoyama et al., "Leakage Current Mechanism of Amorphous and Polycrystalline Ta ₂ O ₅ Films Grown by chemical Vapor Deposition," 1995, pages 977-983.					
	AS	Stemmer et al., "Accommodation of nonstoichiometry in (100) fiber-textured ... thin films grown by chemical vapor deposition," ©1999 American Institute of Physics, pages 2432-2434.					
[Signature]	AT	Streiffer et al., "Ferroelectricity in thin films: The dielectric response of fiber-textured ... thin films grown by chemical vapor deposition," ©1999 American Institute of Physics, pages 45654575.					
EXAMINERS [Signature]				DATE CONSIDERED 12/10/94			
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LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Vishnu K. Agarwal et al.		FILING DATE Aug. 30, 1999		
				GROUP 2815				
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
<i>[Signature]</i>	AA	5,702,562	12/97	Wakahara				
	AB	5,719,417	02/98	Roeder et al.				
	AC	5,723,361	03/98	Azuma et al.				
	AD	5,736,759	04/98	Hausaalter				
	AE	5,976,990	11/99	Mercaldi et al.				
	AF	5,989,927	11/99	Yamonobe				
	AG	6,101,085	08/00	Kawahara et al.				
	AH	6,215,650	04/01	Gnade et al.				
	AI	6,258,654	07/01	Gocho				
	AJ	6,287,935	09/01	Coursey				
	AK	6,325,017 B1	12/01	DeBoer et al.				
	AL	6,335,049 B1	01/02	Basceri				
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AM	JP 04-24922	01/92	Japan - Mitsubishi			X	
	AN	JP 04-115533	04/92	Japan - Oki Elec.			X	
	AO	JP 04-180566	06/92	Japan - Mitsuhsita			ABS	
	AP	JP 08-060347	03/96	Japan - Fujitsu			X	
	AQ	EP 0 810 666 A1	12/97	EPO - Oki Electric			N/A	
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
	AR							
	AS							
	AT							
EXAMINER				DATE CONSIDERED				
<i>[Signature]</i>				12/10/04				
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				FILING DATE Aug. 30, 1999		
				GROUP 2815		
U.S. PATENT DOCUMENTS						
*Examiner Initial	AA	Document Number	Date	Name	Class	Subclass
 		6,566,147 B2	05/03	Basceri et al.		
	AB					
	AC					
	AD					
	AE					
	AF					
	AG					
	AH					
	AI					
	AJ					
	AK					
	AL					
FOREIGN PATENT DOCUMENTS						
		Document Number	Date	Country	Class	Subclass
 	AM	EP 0 892 426 A2	01/99	EPO - Ramtron		
	AN	JP 2000091333	03/00	Japan		
	AO	WO 01/16395	03/01	WIPO - Micron		
	AP					
	AQ					
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)						
	AR					
	AS					
	AT					
EXAMINER				DATE CONSIDERED		
				12/10/4		
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